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Machine Learning Applied to Medical Image Analysis

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Deadline for manuscript submissions:

closed (31 July 2021)

Message from the Guest Editors

This Special Issue is aimed at presenting the state-of-theart, current challenges and future trends for the successful application of ML (Machine Learning) to medical imaging. Original contributions considering recent findings in theory, methodologies, and applications in the field of ML for medical image analysis are welcome. Potential topics include but are not limited to:

- Medical image segmentation;
- Shape modeling of anatomical structures;
- Multimodal medical image registration;
- Lesion detection;
- Temporal prediction of disease evolution;
- Brain connectivity;
- Transfer learning and domain adaptation.

Welcome to contribute!











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Message from the Editor-in-Chief

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